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Kushibiki, J.; Ohashi, Y.; Ono, Y.; Sasamata, T.;
Ultrasonics, Ferroelectrics and Frequency Control, IEEE Transactions on
Volume 49, Issue 7, July 2002 Page(s):905 - 914
[AbstractPlus](#) | Full Text: [PDF](#)(1234 KB) IEEE JNL

- ☐ 2. **Two layers position control system of a manipulator using feed forward control**
Faress, K.N.S.; El-Hagry, M.M.T.;
Electrical and Computer Engineering, 2001. Canadian Conference on
Volume 1, 13-16 May 2001 Page(s):661 - 665 vol.1
[AbstractPlus](#) | Full Text: [PDF](#)(244 KB) IEEE CNF

- ☐ 3. **Electronic beam steering using a varactor-tuned impedance surface**
Sievenpiper, D.; Schaffner, J.; Loo, B.; Tantonan, G.; Harold, R.; Pikulski, J.; Garcia, R.
Antennas and Propagation Society International Symposium, 2001. IEEE
Volume 1, 8-13 July 2001 Page(s):174 - 177 vol.1
[AbstractPlus](#) | Full Text: [PDF](#)(160 KB) IEEE CNF

- ☐ 4. **Space Interferometry Mission System testbed-3: external metrology inversion**
Alvarez-Salazar, O.S.; Azizi, A.;
Aerospace Conference, 2004. Proceedings. 2004 IEEE
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